Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
[barcode]	10/659,624	GOUO, AKIO
	Examiner	**Art Unit**	
	Paul D. Kim	3729	

SEARCHED			
Class	Subclass	Date	Examiner
29	603.03 603.05 603.06	7/21/2005	PK
324	210 212	7/28/2005	PK
360	244.1 244.2		
	245.8	↓	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
PGPub Text Search See attachment		1/31/2006	PK

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Reviewed Parent Application 09/748,918 US PAT. 6,690,546	7/21/2005	PK
Text Search EAST/NPL (IEEE)	7/21/2005	PK
Consuted by David Shindler (324)	7/28/2005	PK
Consuted by Criag Renner (360)	7/28/2006	PK
Updated Text Search EAST	7/28/2006	PK
PGPub Text Search EAST	1/31/2006	PK